PCN Number:	20190725001.1	PCN Date:	Jul 29, 2019
Title:	Qualification of additional Fab site (DMOS6) and Assembly site (JCAP) options for select devices		
Customer Contact:	PCN Manager	Dept:	Quality Services
Proposed 1st Ship Date:	Oct 29, 2019	Estimated Sample Availability:	Date provided at sample request.

Change Type:

☒	Assembly Site	☐	Assembly Process	☐	Assembly Materials
☐	Design	☐	Electrical Specification	☐	Mechanical Specification
☐	Test Site	☐	Packing/Shipping/Labeling	☐	Test Process
☐	Wafer Bump Site	☐	Wafer Bump Material	☐	Wafer Bump Process
☒	Wafer Fab Site	☐	Wafer Fab Materials	☐	Wafer Fab Process
		☐	Part number change		

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of an additional fab (DMOS6) and assembly (JCAP) site for selected devices as listed below in the product affected section.

Current Fab Site			Additional Fab Site		
Current Fab Site	**Process**	**Wafer Diameter**	**Additional Fab Site**	**Process**	**Wafer Diameter**
RFAB	LBC8	300 mm	DMOS6	LBC8	300 mm

There are no material difference between devices currently manufactured and devices built with this manufacturing option.

Reason for Change:

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Anticipated impact on Material Declaration

☒	No Impact to the Material Declaration	☐	Material Declarations or Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained from the TI ECO website.

Changes to product identification resulting from this PCN:

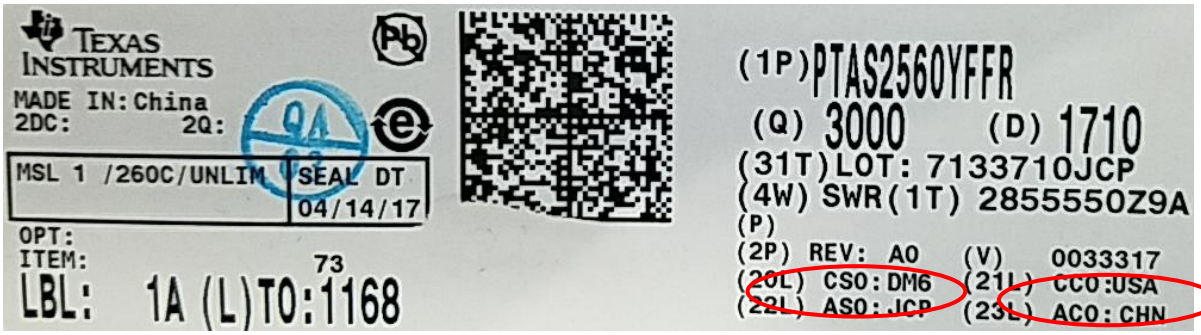
Fab Site Information:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
RFAB	RFB	USA	Richardson
DMOS6	**DM6**	**USA**	**Dallas**

Assembly Site Information:

Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City
TI Clark	QAB	PHL	Angeles City, Pampanga
JCAP	**JCP**	**CHN**	**Jiangyin**

Sample product shipping label (not actual product label)



Product Affected:

AFE4410YZR	AFE4410YZT

Qualification Report

Approve Date 17-Jul-2019

Qualification Results
Data Displayed as: Number of lots / Total sample size / Total failed

	Type	Test Name / Condition	Duration	Qual Device: AFE4410YZR	QBS Product Reference: AFE4900YZR	QBS Process Reference: TAS2552YFF	QBS Process Reference: TAS2553YFF	QBS Package Reference: LM3566YFFR	QBS Package Reference: SN2025YFF
	CDM	ESD - CDM	1000 V	1/3/0	1/3/0	-	-	-	-
	ED	Electrical Characterization	Per Datasheet Parameters	1/30/0	1/Pass	-	3/Pass	3/90/0	-
	ED	Incremental Electrical Char.	Full Temp & Voltage range	-	-	-	-	-	1/Pass
	ELFR	Early Life Failure Rate, 125C	48 Hours	-	-	-	3/3000/0	-	-
	HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	3/231/0	-	3/229/0	2/154/0
	HBM	ESD - HBM	1000 V	1/3/0	-	-	-	-	-
	HTOL	Life Test, 125C	1000 Hours	-	-	-	3/231/0	6/329/0	-
	HTOL	Life Test, 125C	500	1/80/0	1/80/0	-	-	-	-
	HTSL	High Temp Storage Bake 170C	420 Hours	-	1/77/0	3/228/0	-	3/165/0	1/45/0
	LU	Latch-up	(Per JESD78)	1/6/0	1/6/0	-	3/18/0	4/24/0	-
	PD	Physical Dimensions	(per mechanical drawing)	-	-	-	-	-	1/10/0
	SBS	Bump Shear	Solder Bumps	-	-	3/108/0	-	-	-
	SBS	Bump-shear	Per assembly site spec	-	-	-	-	-	1/Pass
	TC	Temperature Cycle, -55/125C	700 Cycles	-	1/78/0	3/231/0	-	-	1/77/0
	TC	Temperature Cycle, -65/150C	500/Cycles - -65C/150C	-	-	-	-	3/240/0	-

	Type	Test Name / Condition	Duration	Qual Device: AFE4410YZR	QBS Product Reference: AFE4900YZR	QBS Process Reference: TAS2552YFF	QBS Process Reference: TAS2553YFF	QBS Package Reference: LM3566YFFR	QBS Package Reference: SN2025YFF
	UHAST	Unbiased HAST 110C/85%RH	264	-	1/77/0	-	-	-	-
	UHAST	Unbiased HAST 130C/85%RH	96 Hours	-	-	3/228/0	-	3/239/0	1/77/0

- QBS: Qual By Similarity
- Qual Device SN1712025YZR is qualified at LEVEL1-260C
- Qual Device AFE4900YZR is qualified at LEVEL1-260C
- Qual Device AFE4410YZR is qualified at LEVEL1-260C
- Qual Device SN1605049YZR is qualified at LEVEL1-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the contacts shown below or your local Field Sales Representative.

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